10/586924 IAP11 Rec'd PCT/PTO 24 JUL 2006

Docket No.

291923US0PCT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Minoru SENGA, et al.

SERIAL NO: New US PCT Application Based on PCT/JP05/01323

GAU:

FILED:

Herewith

EXAMINER:

FOR:

Herewith

LITHIUM ION CONDUCTING SULFIDE BASED CRYSTALLIZED GLASS AND METHOD FOR

PRODUCTION

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS ALEXANDRIA, VIRGINIA 22313

SIR:

Applicant(s) wish to disclose the following information.

REFERENCES

- The applicant(s) wish to make of record the references cited in the International Search Report and listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- Attached is a list of applicant's pending application(s), published application(s) or issued patent(s) which may be related to the present application. In accordance with the waiver of 37 CFR 1.98 dated September 21, 2004, copies of the cited pending applications are not provided. Cited published and/or issued patents, if any, are listed on the attached PTO form 1449.
- A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- □ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number <u>15-0030</u>. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

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LIST OF	REFE	RENCES CITED BY A	APPLICANT	Minoru SENGA, et al.	Minoru SENGA, et al.				
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		·		U.S. PATENT DOCUMENTS					
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	L	DOCUMENT NUMBER	DATE	COUNTRY		TRANSLATION YES NO			
	AO	2002 109955	4/12/2002	JP (with English abstract)				NO	
	AP	2003 208919	7/25/2003	JP (with English abstract)				NO	
	AQ	11 144523	5/28/1999	JP (with English abstract)				NO	
	AR	07 330312	12/19/1995	JP (with English abstract)				NO	
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)									
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